Wafer Carrier Measurement System





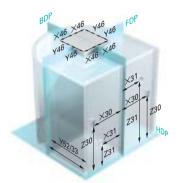
## Wafer Carrier Measurement System

# NEXIV VMR-C4540



NEXIV

- Detects hard-to-see edges such as latch key edges using a variety of illumination as well as Nikon's unique image processing technologies.
- Incorporates Laser AF that provides quick non-contact focusing, even on
- transparent surfaces and on the edge of the peripheries of the wafer, to measure SEMI-standard dimensions with
- excellent accuracy and at high speed.
- Designed for 300mm, 200mm, 150mm,
  125mm wafer carriers.





Measurements of the door



Measurement of the

obotic handle

Measurement of the bottom plane with an adapter

#### **Features**

#### **Designed for 300mm wafer carriers**

A joint development by Nikon and SELETE\*, the VMR-C4540 is a dedicated wafer carrier measurement system designed to manage dimensional accuracy. It provides all dimensional measurements required for wafer carrier fabrication, including control of deformation due to aging of wafers and of wafer carriers. \*Semiconductor Leading Edge Technologies, Inc.

#### Compatible wafer carriers:

- 300mm FOUP - 200mm (with a dedicated adapter)
- 300mm FOSB - 150mm (with a dedicated adapter)
- 300mm - 125mm (with a dedicated adapter)
- SMIF Pod door (with a dedicated adapter)
- Reticle SMIF Pod (with a dedicated adapter)

#### SEMI-standard dimensions

The VMR-C4540 can measure SEMI-specified dimensions that will affect the reliability of wafer carriers, including the door shield, opening and closing, the transfer of wafers, as well as the wafer's "sit" position to FDP.

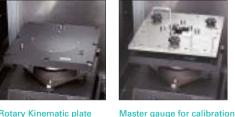
#### Points that can be measured:

- Carrier: latch key, registration pin, robotic handle, door flange, bottom plane (adapter is necessary), etc.
- Wafer position: "sit" position, height at both front and rear ends - Compliant SEMI standards:

SEMI E1.9 Cassette, SEMI E57 Kinematic Coupling, SEMI E47.1 FOUP, SEMI E62 FIMS, SEMI M31 FOSB

#### **Kinematic plate**

The VMR-C4540 uses a SEMI-compliant Kinematic plate to perform precision measurements based on HDP (Horizontal Datum Plane), BDP (Bilateral Datum Plane), and FDP (Facial Datum Plane).

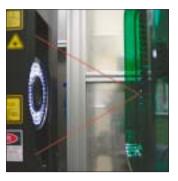


Rotary Kinematic plate



#### Non-contact, fully automated measurement

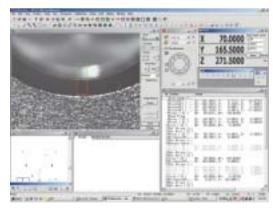
The VMR-C4540 can measure the four planes of the workpiece carrier by rotating the Kinematic plate on which the workpiece is placed in steps of 90°. Measurement of the bottom of the carrier is also possible with an adapter. The measurement head with an objective lens having a 160mm ultra-long working distance moves in 3D directions, allowing non-contact measurement of all measurement points, including the robotic handle. Dedicated software makes possible fully automatic continuous measurement of the four planes of the workpiece carrier.



Laser AF focused on the edge of the peripheries of a wafer













LED 8-segment oblique illuminators surrounding the objective lens







#### Features

### Laser AF

The VMR-C4540 features Laser AF allowing perfect focusing even on transparent surfaces. This enables measurements of the wafer's "sit" positions and the door surface over seal from FDP without making contact with the workpiece.

#### Leading-edge video measurement technologies

The VMR-C4540 utilizes advanced video measurement technologies of the industry-acclaimed Nikon Video Measuring System, NEXIV series , including long working-distance objective lenses, 5-step 10X high-speed zoom, and wide choices of illumination. The available illumination includes LED 8-segment oblique and LED diascopic, as well as coaxial episcopic illumination. The oblique illumination projected from 8 directions emphasizes edges hard to see allowing these edges to be detected accurately by gray scale processing. A dedicated LED diascopic illuminator is designed for measuring wafer heights.

#### Five-step 10X high-speed zoom

Optical magnification	0.27×	0.54×	0.81×	1.66×	2.74×
Field of view (with 1/2-in, CCD)	20×16	10×8	6.0×4.8	3.3×2.6	2.0×1.6
(with 1/2-In. CCD)					Unit <sup>,</sup> mm

#### High speed, high throughput

The rotary Kinematic plate provides continuous measurements of all four planes of the workpiece carrier. Nikon's top-notch technologies nurtured through the development of the NEXIV series, non-contact measurement, the head's rapid 200mm/sec. travel speed, and high-speed video processing all combine to achieve high throughput for measurements of large quantities of carriers with excellent efficiency.

#### **Dedicated measurement software**

Based on the NEXIV VMR software programs known for their easy operation, Nikon has developed a dedicated software program expressly for the new carrier measurement system. It allows a series of measurement procedures to be automated by CNC Replay. If you create an evaluation program by freely selecting teaching programs for each plane, the system can measure all four planes in a single process.

#### Data is easily adaptable

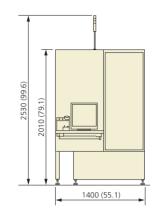
Measurement results can be saved as CSV files, facilitating later processing and modification. The wafer carrier ID number, which may be the name of CSV files, can also be read by a barcode reader (option). Measuring results can be transmitted through an RS-232C port or a LAN network.

#### Specifications

Compatible wafer carriers	SEMI-compliant 300mm wafer carriers (FOUP, FOSB, etc.) and	
	200mm, 150mm, 125mm wafer carriers (with dedicated adapter)	
Stroke	480 x 180 x 400mm (18.9 x 7.1 x 15.7 in.)	
(Measurement head; X x Y x Z		
Rotary Kinematic plate	360° (in steps of 90°)	
Minimum readout	0.1µm	
Head travel speed	XZ axis: 200mm/sec. max.; Y axis: 50mm/sec.	
Kinematic plate rotation speed	90°/2 sec.	
Camera	Black & white 1/2-in. CCD	
Optical magnification	0.27X—2.75X (5-step 10X zoom)	
Field of view	20 x 16mm—2.0 x 1.6mm	
Maximum workpiece weight	: 15kg (33.1 lb.)	
Measurement accuracy	10 + 10L/1000 µm (L: measurement length in mm)	
Repeatability	2µm (2 sigma)	
Illumination	Coaxial episcopic, diascopic, 8-segment oblique illumination	
Autofocus	Laser AF	
Power source	AC 100-120V or 200-240V±10%, 50/60Hz	
Power consumption	13A (at AC 100-120V), 7A (at AC 200-240V) excluding PC	
Dimensions & weight	1400 (W) x 1500 (D) x 2010 (H)mm, approx. 1400kg	
	(55.1 x 59.1 x 79.1 in., 3086.4 lb.)	
Host computer	IBM PC/AT (Windows®2000)	
Monitor	17-in. SXGA TFT LCD	

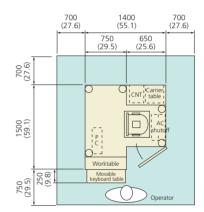
#### Dimensional Diagram

Unit: mm (inches)



#### Footprint

Unit: mm (inches)



Laser AF is a Class 1 Laser Product



Specifications and equipment are subject to change without any notice or obligation on the part of the manufacturer. April 2007 ©2003-07 NIKON CORPORATION

WARNING TO ENSURE CORRECT USAGE, READ THE CORRESPONDING MANUALS CAREFULLY BEFORE USING YOUR EQUIPMENT.

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